ST3DV520A



High bandwidth switch with 20- to 10-bit MUX/DEMUX

Datasheet - production data

Features

■ Low R_{ON} : 4.0 Ω typical

■ V_{CC} operating range: 3.0 to 3.6 V

■ Enhanced ESD protection: > 8 kV (contact) and 15 kV (HBM)

■ Channel on capacitance: 9.5 pF typical

■ Switching time speed: 9 ns

Near to zero propagation delay: 250 ps
 Very low crosstalk: -45 dB at 250 MHz

■ Bit-to-bit skew: 200 ps

> 600 MHz -3 dB typical bandwidth (or data frequency)

■ Package: QFN56

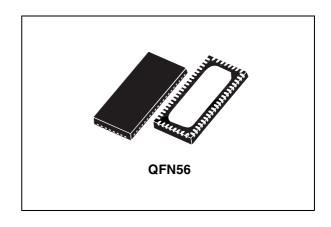


Table 1. Device summary

Order code	Package	Packing
ST3DV520AQTR	QFN56	Tape and reel

Contents ST3DV520A

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ST3DV520A Description

1 Description

The ST3DV520A 20- to 10-bit multiplexer/demultiplexer is a high bandwidth bidirectional switch with low R_{ON} suitable for analog video applications.

The signal from each input is multiplexed into one of two selected outputs, while the unselected switch goes into Hi-Z status. The device is designed for very low crosstalk, low bit-to-bit skew and low I/O capacitance.

The ST3DV520A supports high definition (HD) video switching standards and is also suitable for general-purpose switching that requires high signal integrity.

Pin description ST3DV520A

2 Pin description

Figure 1. Pin connection (top through view)

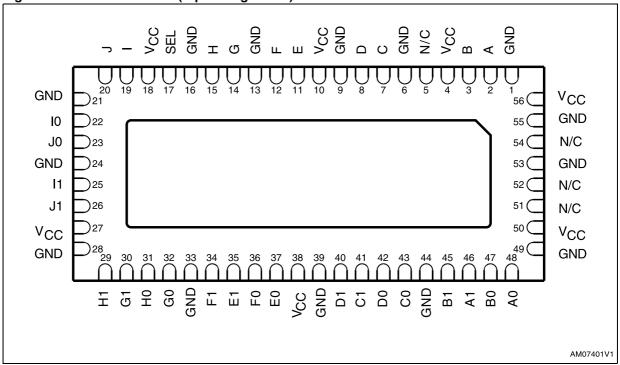


Table 2. Pin description

Pin	Pin Symbol	
2, 3, 7, 8, 11, 12, 14, 15, 19, 20	A, B, C, D, E, F, G, H, I, J	10-bit bus
48, 47, 43, 42, 37, 36, 32, 31, 22, 23	A0, B0, C0, D0, E0, F0, G0, H0, I0, J0	10-bit multiplexed to bus 0
46, 45, 41, 40, 35, 34, 30, 29, 25, 26	A1, B1, C1, D1, E1, F1, G1, H1, I1, J1	10-bit multiplexed to bus 1
5, 51, 52, 54	N/C	Not connected
17	SEL	Bus and LED switch selection
4, 10, 18, 27, 38, 50, 56	V _{CC}	Supply voltage
1, 6, 9, 13, 16, 21, 24, 28, 33, 39, 44, 49, 53, 55	GND	Ground

ST3DV520A Pin description

Figure 2. Input equivalent circuit

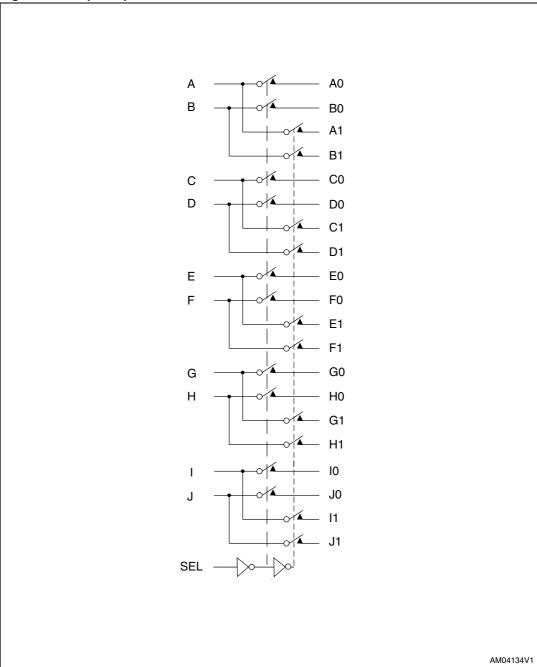


Table 3. Switch function table

SEL	Function
L	10-bit bus to 10-bit multiplexed bus 0
Н	10-bit bus to 10-bit multiplexed bus 1

Maximum ratings ST3DV520A

3 Maximum ratings

Stressing the device above the rating listed in *Table 4: Absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in *Table 5: Recommended operating conditions* of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 4. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{CC}	Supply voltage to ground	-0.5 to 4.6	V
V _{IO}	DC input output voltage	-0.5 to 4.6	V
V _{IC}	DC control input voltage	-0.5 to 4.6	V
Io	DC output current ⁽¹⁾	120	mA
P _D	Power dissipation	0.5	W
T _{stg}	Storage temperature	-65 to 150	°C
TL	Lead temperature (10 sec.)	300	°C

^{1.} If $V_{IO} \times I_{O}$ does not exceed the maximum limit of P_{D} .

Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter		Unit		
	Faranneter	Min.	Тур.	Max.	Onne
V _{CC}	Supply voltage to ground	3	_	3.6	V
V _{IC}	DC control input voltage (SEL)	0	-	5	V
V _{IO}	DC input/output voltage	0	_	V _{CC}	V
T _A	Operating temperature	-40	-	85	°C

4 Electrical characteristics

Table 6. DC electrical characteristics ($V_{CC} = 3.3 \text{ V} \pm 10\%$)

	(-6			Unit		
Symbol	Parameter	Test condition	-40 to 85 °C			
			Min.	Тур.	Max.	
V _{IH}	Voltage input high (SEL)	High level guaranteed	2	-	_	V
V _{IL}	Voltage input low (SEL)	Low level guaranteed	-0.5	-	0.8	٧
V _{IK}	Clamp diode voltage (SEL)	V _{CC} = 3.6 V I _{IN} = -18 mA	-	-0.8	-1.2	٧
I _{IH}	Input high current (SEL)	$V_{CC} = 3.6 \text{ V}$ $V_{IN} = V_{CC}$	-	-	±5	μA
I _{IL}	Input low current (SEL)	V _{CC} = 3.6 V V _{IN} = GND	-	-	±5	μΑ
l _{OFF(SW)} ⁽¹⁾	Leakage current through the switch common terminals (A to J)	$V_{CC} = 3.6 \text{ V}$ A to J = V_{CC} LED1 to LED3 = V_{CC} A0 to J0 = 0 V A1 to J1 = floating SEL = V_{CC}	-	-	±1	μА
I _{OFF(SEL)}	SEL pin leakage current	V _{CC} = 0 V SEL = 0 to 3.6 V	-	-	±1	μA
R _{ON}	Switch ON resistance ⁽²⁾	$V_{CC} = 3.0 \text{ V}$ $V_{IN} = 1.5 \text{ to } V_{CC}$ $I_{IN} = -40 \text{ mA}$	_	4.0	6.5	Ω
R _{FLAT}	ON resistance flatness (2),(3)	V_{CC} = 3.0 V V_{IN} at 1.5 and V_{CC} I_{IN} = -40 mA	-	0.5	-	Ω
Δ R _{ON}	ON resistance match between channel $\Delta R_{ON} = R_{ONMAX} - R_{ONMIN} ^{(2)},^{(4)}$	$V_{CC} = 3.0 \text{ V}$ $V_{IN} = 1.5 \text{ to } V_{CC}$ $I_{IN} = -40 \text{ mA}$	_	0.4	1	Ω

^{1.} Refer to Figure 4: Test circuit for leakage current (I_{OFF}) on page 11.

^{2.} Measured by voltage drop between channels at indicated current through the switch. ON resistance is determined by the lower of the voltages.

^{3.} Flatness is defined as the difference between the R_{ONMAX} and R_{ONMIN} of ON resistance over the specified range.

^{4.} ΔR_{ON} measured at same V_{CC} , temperature and voltage level.

Table 7. Capacitance ($T_A = 25 \, ^{\circ}C$, $f = 1 \, \text{MHz}$)

Symbol	Parameter	Test condition		Unit		
	raiailletei	rest condition	Min.	Тур.	Max.	Oilit
C _{IN}	SEL pin input capacitance ⁽¹⁾	DC = 0.25 V AC = 0.5 V _{PP} f = 1 MHz	-	2	3	pF
C _{OFF}	Switch off capacitance ⁽²⁾	DC = 0.25 V AC = 0.5 V _{PP} f = 1 MHz	-	4	5	pF
C _{ON}	Switch on capacitance ⁽³⁾	DC = 0.25 V AC = 0.5 V _{PP} f = 1 MHz	-	9.5	11	pF

- 1. Refer to Figure 5 on page 11.
- 2. Refer to Figure 6 on page 12.
- 3. Refer to Figure 7 on page 12.

Table 8. Power supply characteristics

				Value		
Symbol	Parameter	Test condition	-40 to 85 °C		Unit	
			Min.	Тур.	Max.	
I _{CC}	Quiescent power supply	$V_{CC} = 3.6 \text{ V}, V_{IN} = V_{CC} \text{ or GND}$	_	150	500	μΑ

Table 9. Dynamic electrical characteristics ($V_{CC} = 3.3 \text{ V} \pm 10\%$)

Symbol	Parameter	Test condition		-40 to 85 °C	;	Unit
			Min.	Тур.	Max.	
X _{talk}	Crosstalk ⁽¹⁾	R_L = 100 Ω f = 250 MHz	-	-45	-	dB
O _{IRR}	Off isolation ⁽²⁾	R_L = 100 Ω f = 250 MHz	_	-37	_	dB
BW	-3 dB bandwidth ⁽³⁾	$R_L = 100 \Omega$ 0 < $V_{IN} \le 3.6 V$	-	600	_	MHz

- 1. Refer to Figure 9 on page 14.
- 2. Refer to Figure 10 on page 15.
- 3. Refer to Figure 8 on page 13.

Table 10. Switching characteristics ($T_A = 25$ °C, $V_{CC} = 3.3$ V ±10%)

Symbol	Parameter Test condition		Unit			
Symbol	Parameter	rest condition	Min.	Тур.	Max.	Onn
t _{PD}	Propagation delay	V _{CC} = 3 to 3.6 V	_	0.25	-	ns
t _{PZH} , t _{PZL}	Line enable time, SE to x to x0 or x to x1	V _{CC} = 3 to 3.6 V	0.5	6.5	15	ns
t _{PHZ} , t _{PLZ}	Line disable time, SE to x to x0 or x to x1	V _{CC} = 3 to 3.6 V	0.5	6.5	8.5	ns
t _{SK(O)}	Output skew between center port to any other port	V _{CC} = 3 to 3.6 V	-	0.1	0.2	ns
t _{SK(P)}	Skew between opposite transition of the same output (t _{PHL} , t _{PLH})	V _{CC} = 3 to 3.6 V	-	0.1	0.2	ns

Table 11. ESD performance

Symbol	Test condition		Unit		
	rest condition	Min.	Тур.	Max.	Offic
ESD	Contact discharge ⁽¹⁾ IEC61000-4-2	-	±8	-	kV
	Human body model (MIL-STD-883)	-	±15	_	kV

^{1.} Refer to Figure 3: Diagram for suggested V_{CC} decoupling on page 10.

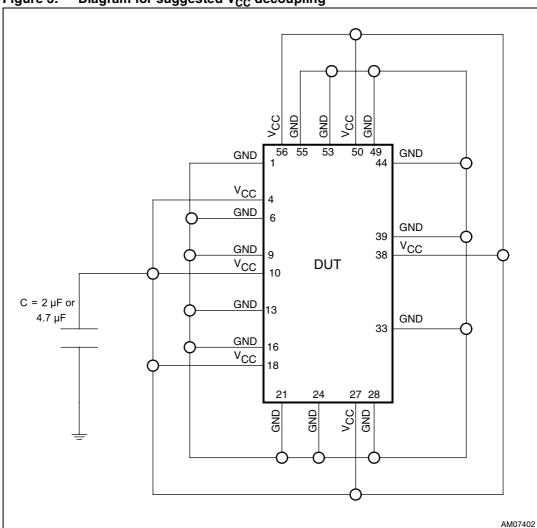


Figure 3. Diagram for suggested V_{CC} decoupling

- 1. Applicable for system level ESD test.
- 2. 100 nF capacitors must be used as local bypass capacitors between the adjacent V_{CC} and GND pairs (total 7).

Test circuit for leakage current (I_{OFF}) v_{CC} I_{OFF}(SW) A0 Α Α1 FLOAT -3.6 V 3.6 V — SEL GND AM07404

Figure 4.



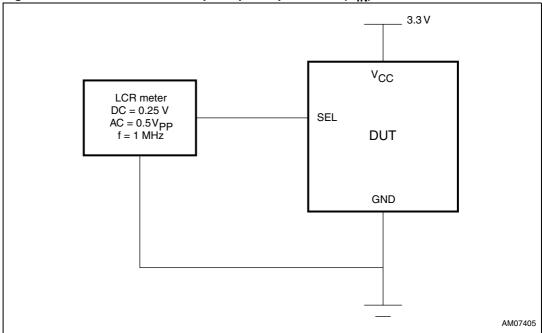


Figure 6. Test circuit for switch off capacitance (C_{OFF})

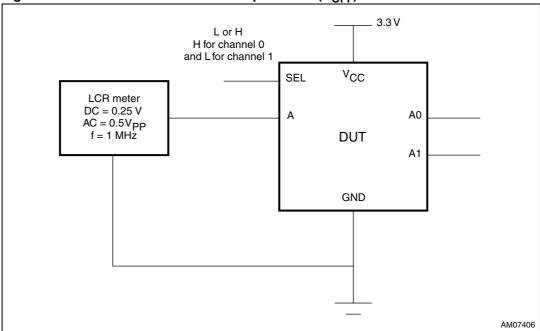
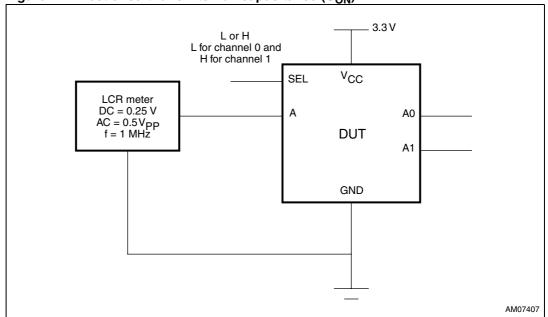


Figure 7. Test circuit for switch on capacitance (C_{ON})



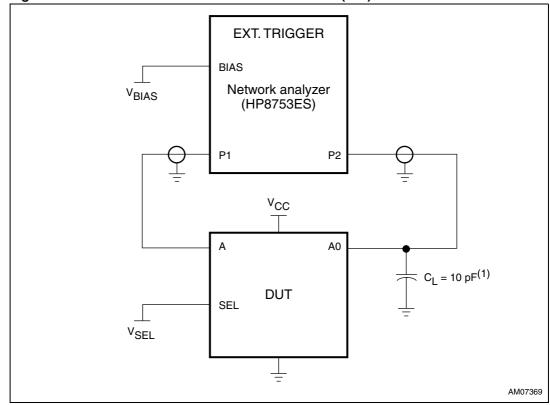


Figure 8. Test circuit for bandwidth measurement (BW)

1. C_L includes probe and jig capacitance.

Frequency response is measured at the output of the ON channel. For example, when $V_{SEL} = 0$ and A is the input, the output is measured at A0. All unused analog I/O ports are left open.

HP8753ES setup:

Average = 4

 $R_{BW} = 3 \text{ kHz}$

 $V_{BIAS} = 0.35 V$

ST = 2 s

P1 = 0 dBm

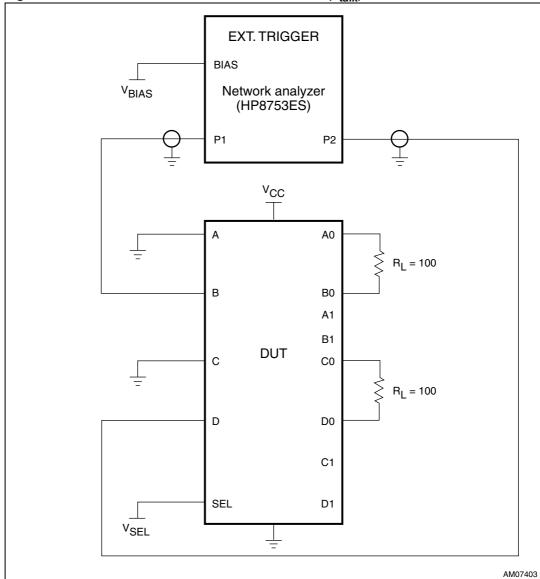


Figure 9. Test circuit for crosstalk measurement (x_{talk})

- 1. C_L includes probe and jig capacitance.
- 2. A 50 $\Omega\,\text{termination}$ resistor is needed to match the loading of the network analyzer.

Crosstalk is measured at the output of the non-adjacent ON channel. For example, when $V_{SEL} = 0$, and B is the input, the output is measured at D. All unused analog input ports are connected to GND and output ports are left open.

HP8753ES setup:

Average = 4

 $R_{BW} = 3 \text{ kHz}$

 $V_{BIAS} = 0.35 V$

ST = 2 s

P1 = 0 dBm

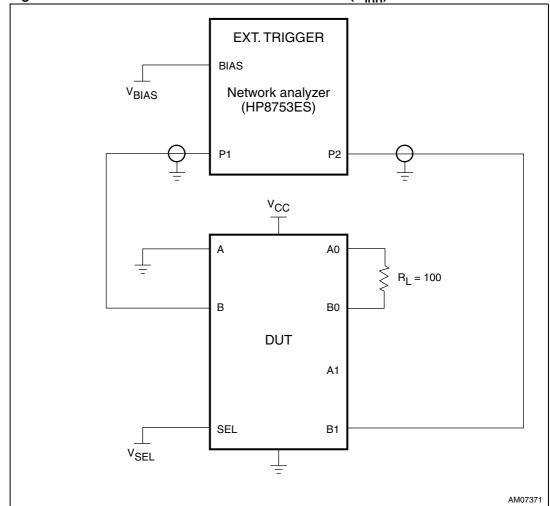


Figure 10. Test circuit for off isolation measurement (O_{IRR})

- 1. C_L includes probe and jig capacitance.
- 2. A 50 $\Omega\,\text{termination}$ resistor is needed to match the loading of the network analyzer.

Off isolation is measured at the output of the OFF channel. For example, when $V_{SEL} = 0$, and B is the input, the output is measured at B1. All unused analog input ports are connected to GND and output ports are left open.

HP8753ES setup:

Average = 4

 $R_{BW} = 3 \text{ kHz}$

 $V_{BIAS} = 0.35 V$

ST = 2 s

P1 = 0 dBm

Package information ST3DV520A

5 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

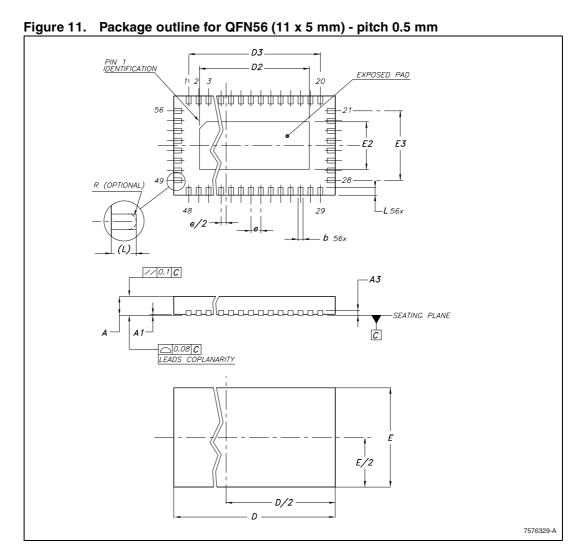
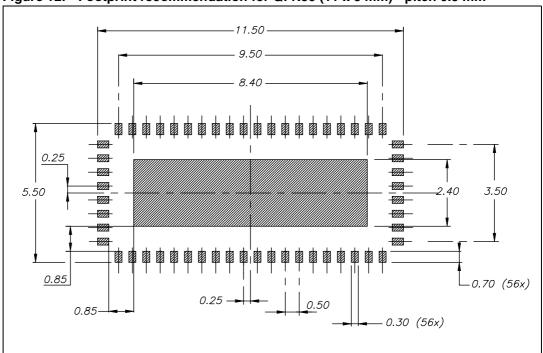


Table 12. Mechanical data for QFN56 (11 x 5 mm) - pitch 0.5 mm

Symbol	Millimeters		
	Min.	Тур.	Max.
A	0.70	0.75	0.80
A1	_	_	0.05
А3		0.20	-
b	0.20	0.25	0.30
D	10.90	11.00	11.10
D2	8.30	8.40	8.50
D3	-	9.50	-
E	4.90	5.00	5.10
E2	2.30	2.40	2.50
E3	_	3.50	-
е	_	0.50	-
L	0.30	0.40	0.50

Figure 12. Footprint recommendation for QFN56 (11 x 5 mm) - pitch 0.5 mm



Package information ST3DV520A

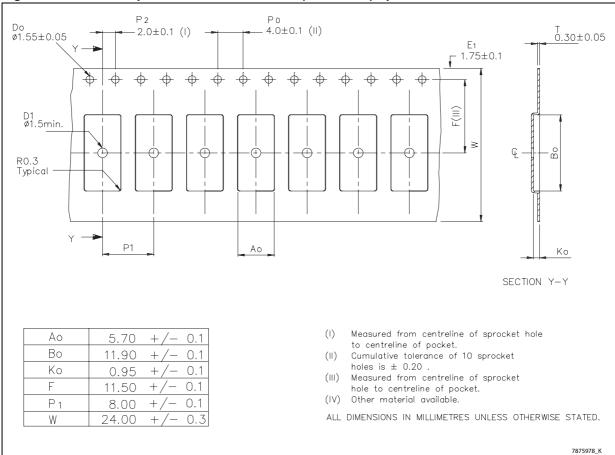


Figure 13. Carrier tape information for QFN56 (11 x 5 mm) - pitch 0.5 mm

ST3DV520A Package information

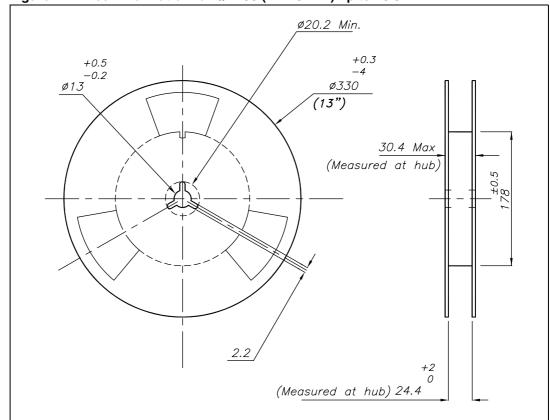


Figure 14. Reel information for QFN56 (11 x 5 mm) - pitch 0.5 mm

Revision history ST3DV520A

6 Revision history

Table 13. Document revision history

Date	Revision	Changes
11-Dec-2009	1	Initial release.
07-Apr-2010	2	Corrected circuit drawing errors in <i>Figure 2: Input equivalent circuit</i> . Modified text in the Description on page 1.
11-Jan-2011	3	Document reformatted, replaced V _{DD} by V _{CC} in <i>Figure 1</i> , <i>Table 2</i> , <i>Figure 3</i> , to <i>Figure 10</i> , moved notes below <i>Figure 8</i> to <i>Figure 10</i> , corrected typo in <i>Table 5</i> to <i>Table 7</i> , <i>Table 9</i> , <i>Figure 3</i> to <i>Figure 10</i> .
17-Jan-2013	4	Updated <i>Figure 1</i> (added numbers to pins) and <i>Table 2</i> (updated order of pins). Added cross-references in <i>Section 3</i> . Minor modifications throughout document.

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